High-Throughput True Random Number Generation Using Quadruple Row Activation in Real DRAM Chips

#### **Ataberk Olgun**

Minesh Patel A. Giray Yağlıkçı Haocong Luo Jeremie S. Kim F. Nisa Bostancı Nandita Vijaykumar Oğuz Ergin Onur Mutlu



## **Executive Summary**

- <u>Motivation</u>: DRAM-based true random number generators (TRNGs) provide true random numbers at low cost on a wide range of computing systems
- **<u>Problem</u>**: Prior DRAM-based TRNGs are slow:
  - 1. Based on fundamentally slow processes  $\rightarrow$  high latency
  - 2. Cannot effectively harness entropy from DRAM rows  $\rightarrow$  low throughput
- <u>Goal</u>: Develop a high-throughput and low-latency TRNG that uses commodity DRAM devices
- <u>Key Observation</u>: Carefully engineered sequence of DRAM commands can activate four DRAM rows → QUadruple ACtivation (QUAC)
- <u>Key Idea</u>: Use QUAC to activate DRAM rows that are initialized with conflicting data (e.g., two '1's and two '0's) to generate random values
- <u>QUAC-TRNG:</u> DRAM-based TRNG that generates true random numbers at highthroughput and low-latency by repeatedly performing QUAC operations
- **<u>Results:</u>** We evaluate QUAC-TRNG using **136** real DDR4 chips
  - 1. **5.4 Gb/s** maximum (**3.4 Gb/s** average) TRNG throughput per DRAM channel
  - 2. Outperforms existing DRAM-based TRNGs by 15.08x (base), and 1.41x (enhanced)
  - 3. Low TRNG latency: **256-bit RN** in **274 ns**
  - 4. Passes all 15 NIST randomness tests

### Outline

#### **True Random Numbers in DRAM**

#### **DRAM Organization and Operation**

## **QUadruple ACtivation (QUAC)**

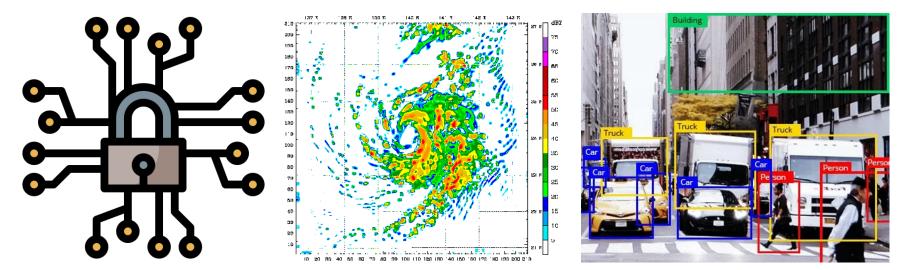
### **QUAC-TRNG**

#### **Evaluation**



#### **Use Cases of True Random Numbers**

# High-quality true random numbers are critical to many applications



True random numbers can **only** be obtained by sampling random physical processes

Unfortunately, not all computing systems are equipped with TRNG hardware (e.g., dedicated circuitry)

### **DRAM-Based TRNGs**

DRAM chips are ubiquitous in modern computing platforms

DRAM-based TRNGs enable true random number generation within DRAM chips

*Low-cost:* No specialized circuitry for RNG

- Beneficial for constrained systems

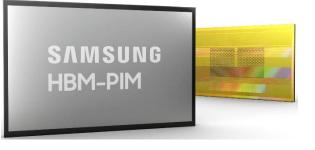
#### *High-throughput:* > Gb/s throughput

- Open application space that require high-throughput TRNG

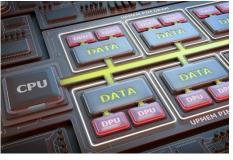
#### **Synergy with Processing-in-Memory**

#### **Processing-in-Memory (PIM) Systems**

- Perform computation directly within a memory chip
- Improve system performance by avoiding off-chip data movement



[Samsung]



[UPMEM]

#### **True random number generation within DRAM**

- Enables PIM workloads to sample true random numbers directly within the memory chip
- Avoids inefficient communication to other possible off-chip TRNG sources, enhances security & privacy

### Outline

#### **True Random Numbers in DRAM**

#### **DRAM Organization and Operation**

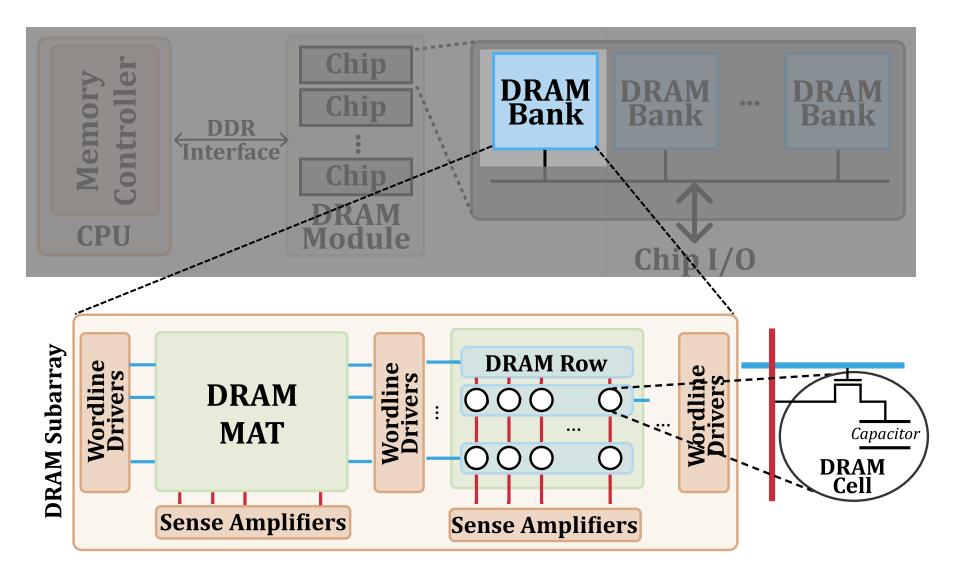
## **QUadruple ACtivation (QUAC)**

### **QUAC-TRNG**

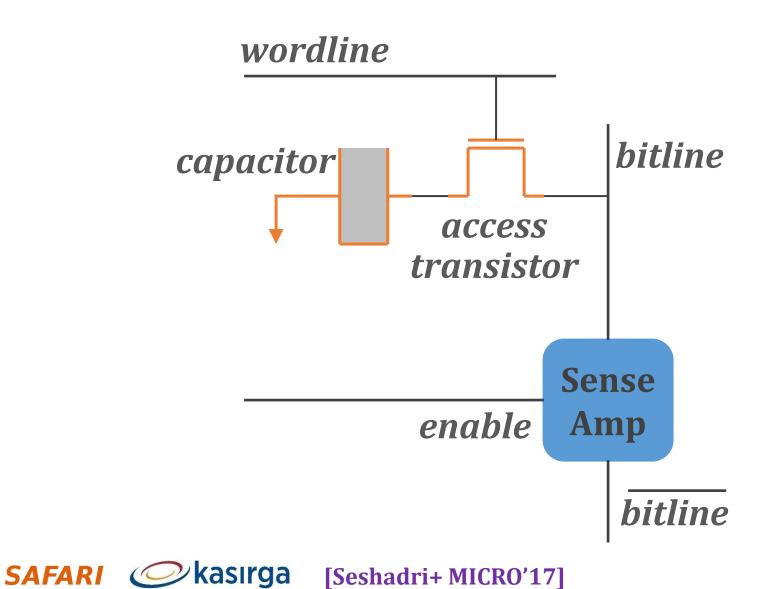
#### **Evaluation**



## **DRAM Organization**

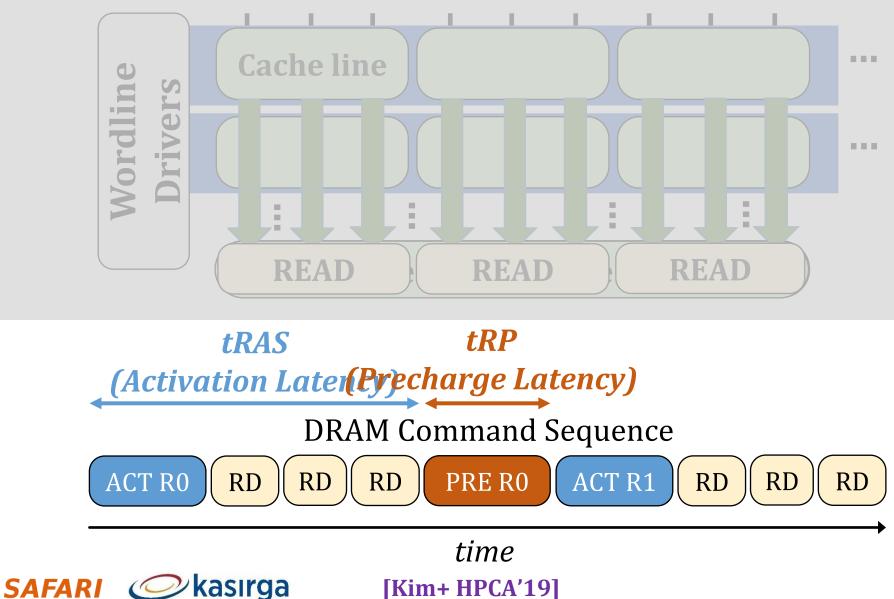


#### **Accessing a DRAM Cell**



#### **Accessing a DRAM Cell** deviation in 4 bitline voltage enable wordline 1 wordline $V_{\partial D} Y_{DD} + \delta$ bitline capacitor access connects cell transistor 3 to bitline cella ast dhange te stitlind Sense enable Amp enable 5 sense amp bitline [Seshadri+ MICRO'17 ≥ kasırga 10SAFARI

## **DRAM Operation**



### Outline

#### **True Random Numbers in DRAM**

**DRAM Organization and Operation** 

## **QUadruple ACtivation (QUAC)**

#### **QUAC-TRNG**

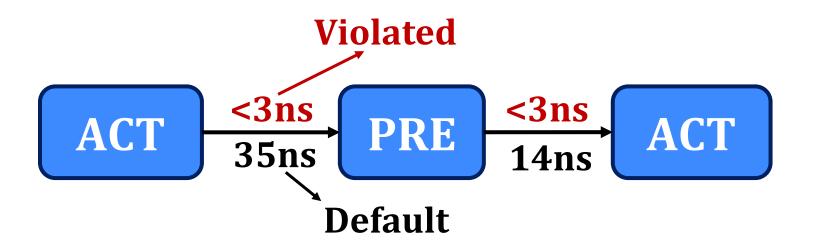
#### **Evaluation**



## **Quadruple Activation (QUAC)**

#### **New Observation**

Carefully-engineered DRAM commands can activate four rows in real DRAM chips

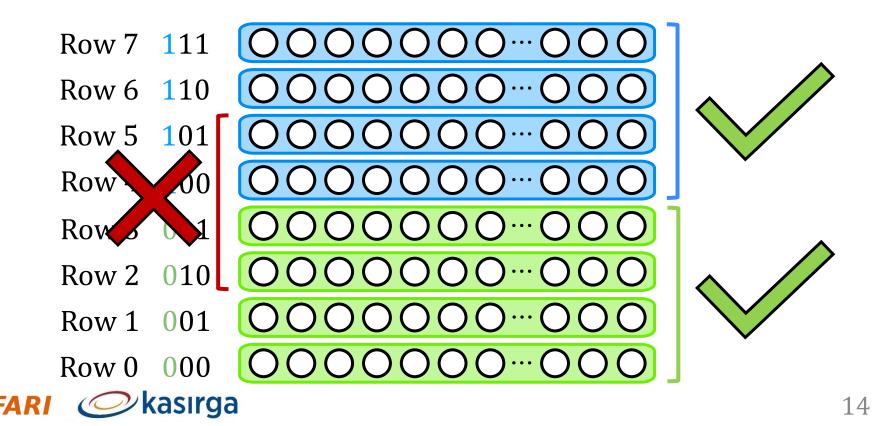


Activate four rows with two ACT commands

## **Quadruple Activation (QUAC)**

#### <u>Characteristic 1</u>

Activates a set of four DRAM rows whose addresses differ only in their two LSBs



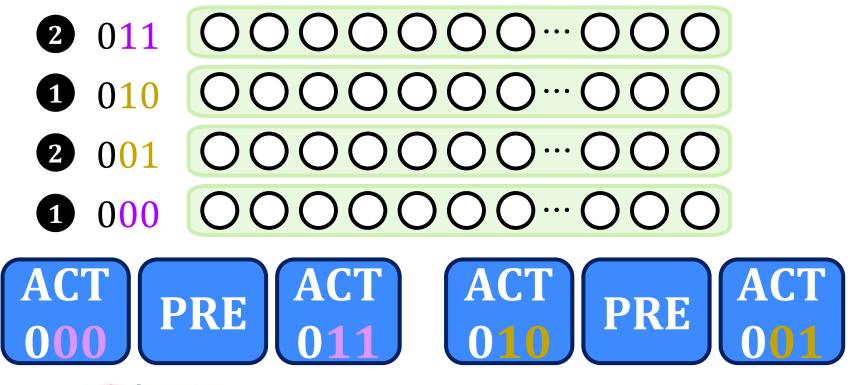
## **Quadruple Activation (QUAC)**

#### <u>Characteristic 2</u>

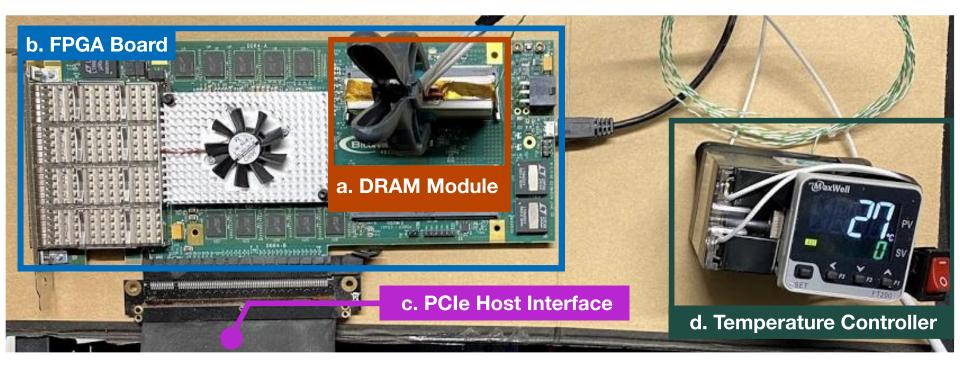
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First and second ACT's addresses must have their two LSBs inverted



## **QUAC on Real DRAM Chips**



## Valid QUAC behavior on 136 DDR4 chips



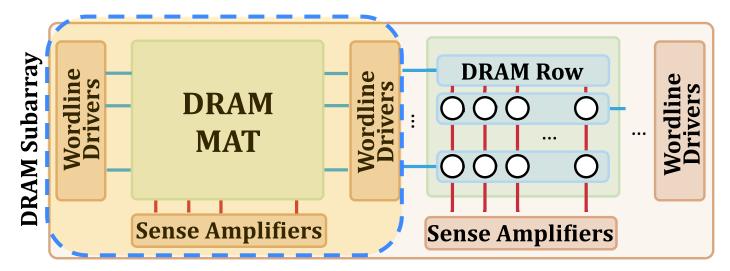
## Why Does QUAC Work?

- **Hypothetical circuit to explain QUAC**
- **Hierarchical Wordlines**
- High *density* and *performance* requirements
- Hierarchical organization of DRAM wordlines enable *high-density* and *low-latency* DRAM operation



## **Hierarchical Wordlines**

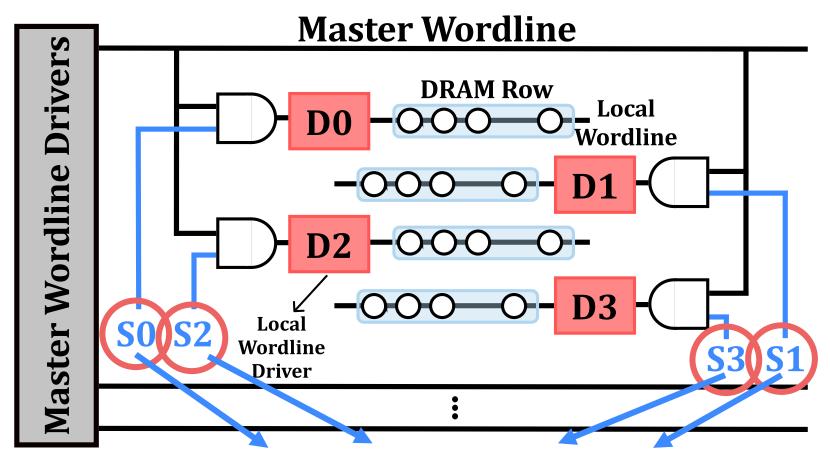
#### A master wordline drives multiple local wordlines





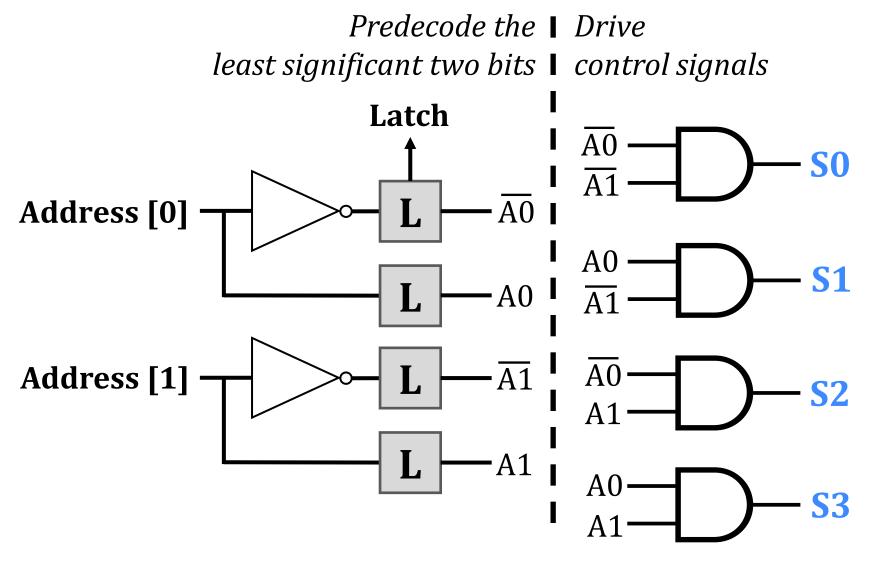
## **Hierarchical Wordlines**

#### A master wordline drives multiple local wordlines

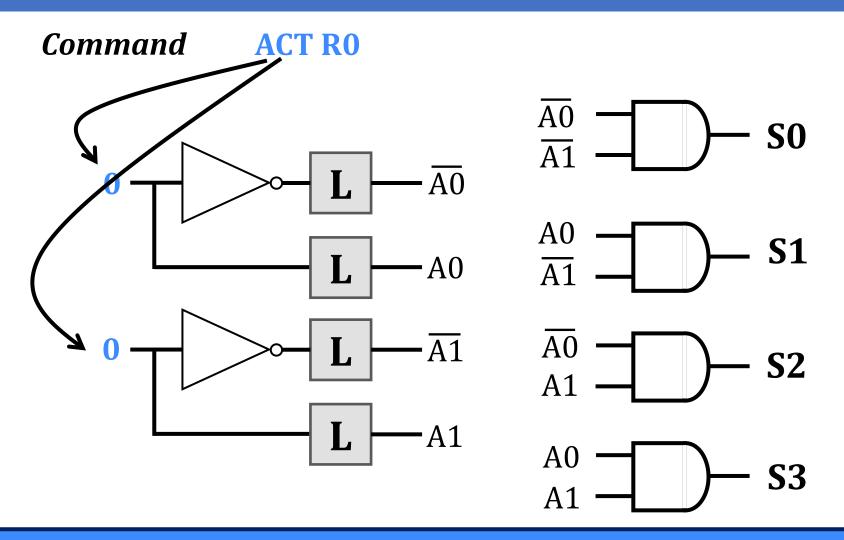


#### Select signals for rows 0-3





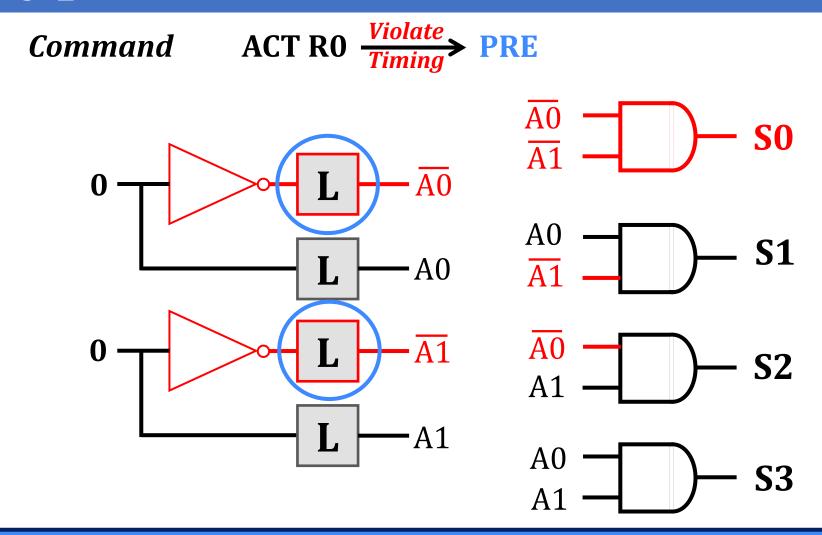




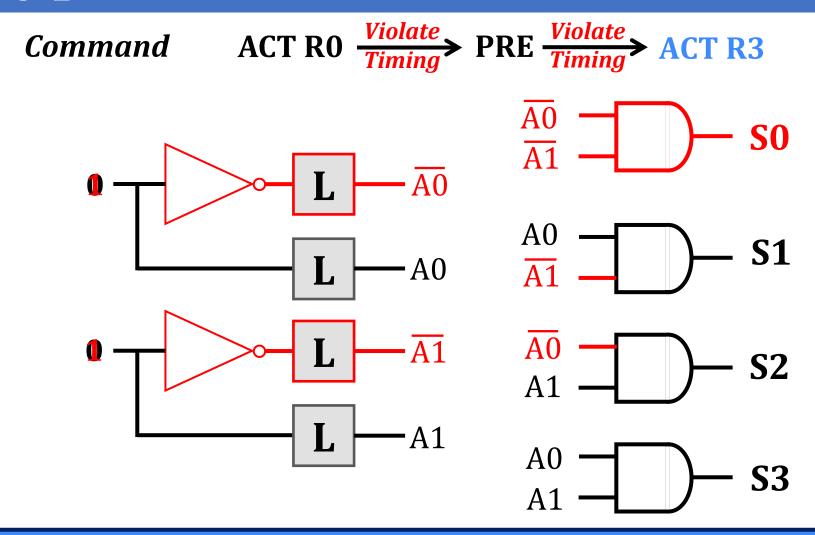
First ACT command drives a single wordline

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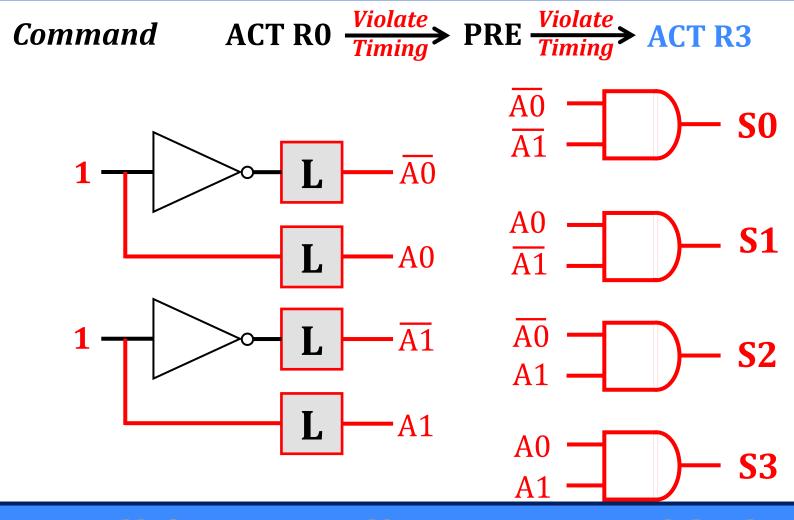


#### PRE command cannot disable latches



Second ACT drives the remaining three wordlines





All four wordlines are enabled Quadruple Activation

### Outline

#### **True Random Numbers in DRAM**

#### **DRAM Organization and Operation**

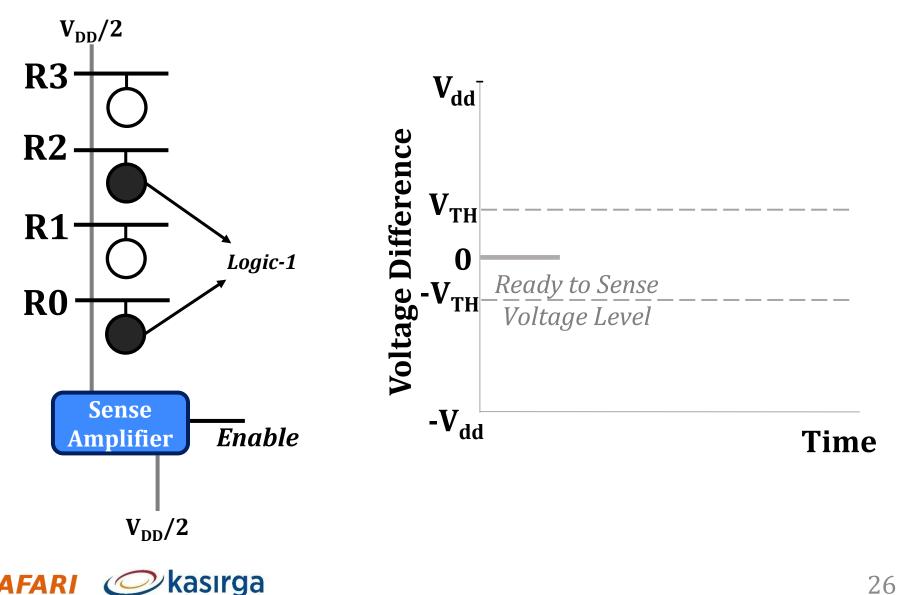
## **QUadruple ACtivation (QUAC)**

## **QUAC-TRNG**

#### **Evaluation**

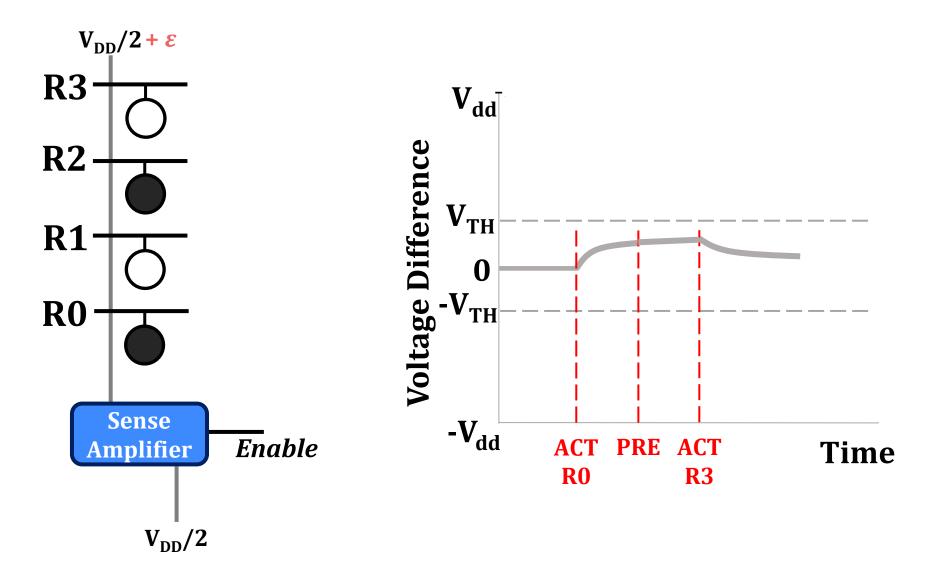


#### **Generating Random Values via QUAC**



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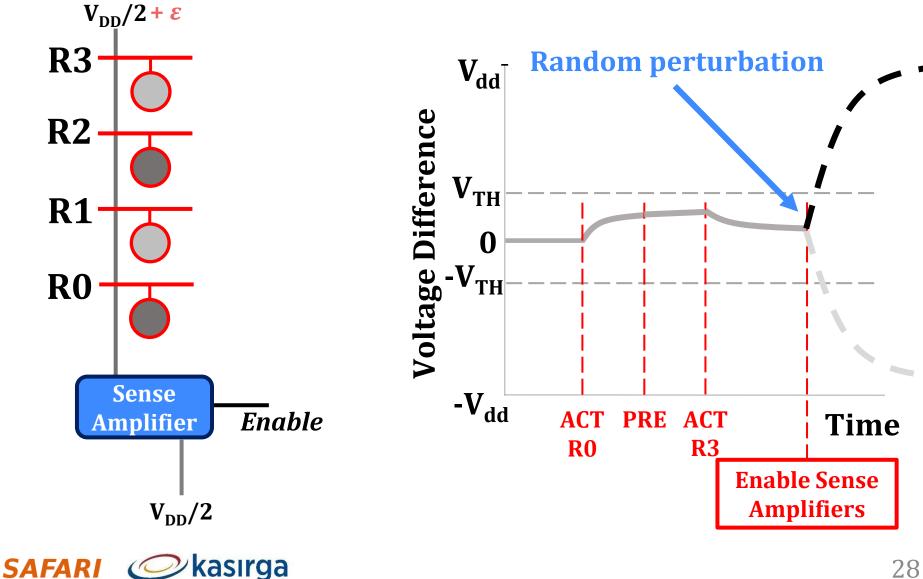


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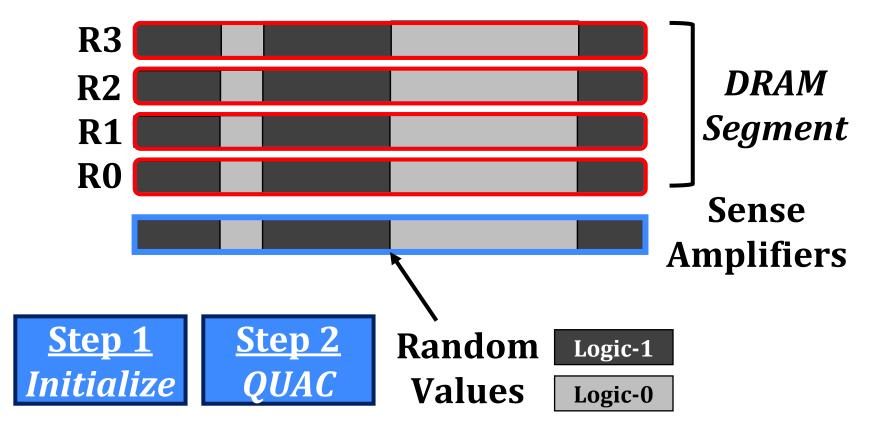
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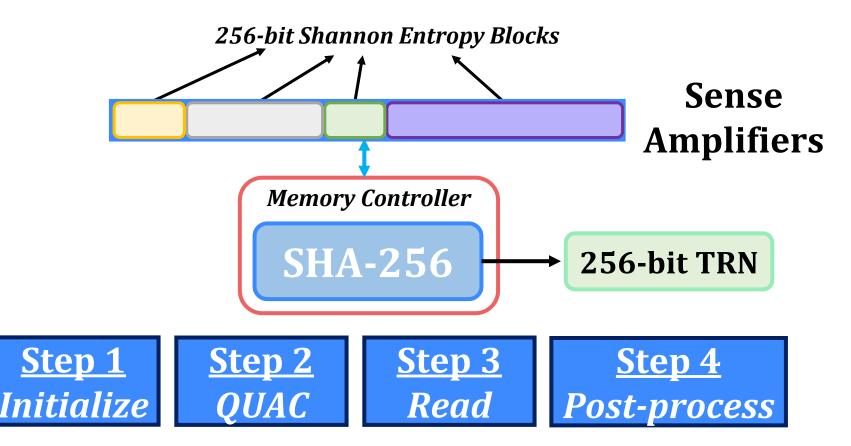
#### **Generating Random Values via QUAC**



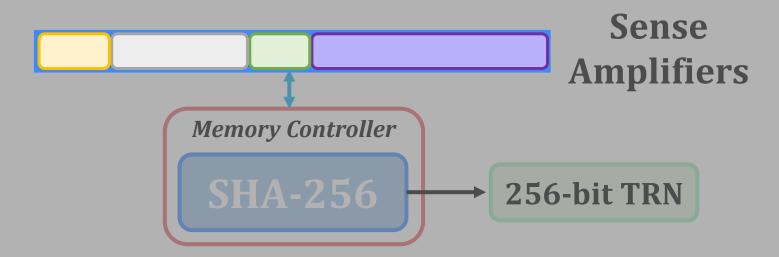
**Key Idea:** Leverage random values on sense amplifiers generated by QUAC operations as source of entropy



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Generates a 256-bit random number for every 256-bit Shannon Entropy block

### Outline

#### **True Random Numbers in DRAM**

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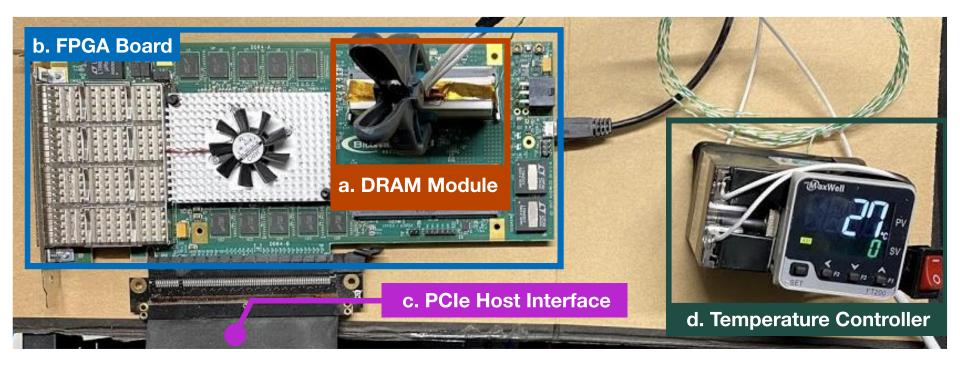
#### **Evaluation**



### **Real Chip Characterization**

Experimentally study QUAC and QUAC-TRNG using 136 real DDR4 chips from SK Hynix

**DDR4 SoftMC →** DRAM Testing Infrastructure



SAFARI @kasirga [Hassan+ HPCA'17] https://github.com/CMU-SAFARI/SoftMC 33

## **Real Chip Characterization**

# Measure randomness of bitstreams using **Shannon Entropy**

$$H(x) = -\sum_{i=1}^{2} p(x_i) \log_2 p(x_i) \longrightarrow \begin{array}{l} \text{Calculating probabilities:} \\ \text{Proportion of } logic-1 \text{ and} \\ logic-0 \text{ values in the random} \\ \text{bitstream} \end{array}$$

Sample each bitline following QUAC *1000 times* and calculate the bitline's Shannon Entropy

## **SE(***1111...111***)** = 0 0 < **SE(***1001...010***)** < 1



## **Real Chip Characterization**

#### At 50°C and nominal voltage:

- Repeatedly perform QUAC 1000 times and measure the Shannon Entropy of each bitline in
- 8K DRAM Segments (32K DRAM Rows),
- using all 16 different four-bit data patterns



### **Data Pattern Dependence**

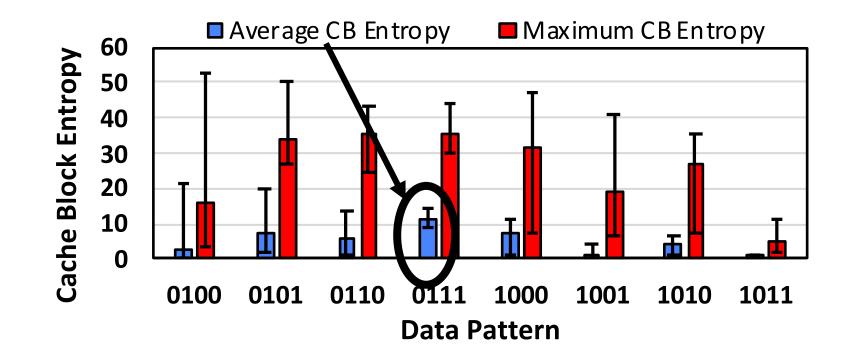
Calculate cache block entropy (CBE)

 $\sum$  all bitline entropies in the cache block

Metrics based on CBE:

- **1.** Average CBE: Average entropy across all cache blocks in a module
- **2.** Maximum CBE: *Maximum* of the cache block entropies in a module

## **Data Pattern Dependence**



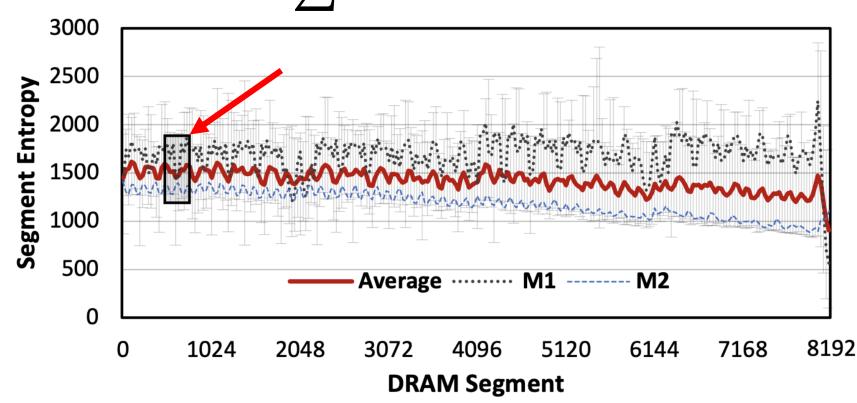
#### **Entropy varies with data pattern**

Highest average entropy with pattern "0111"



# **Spatial Distribution**

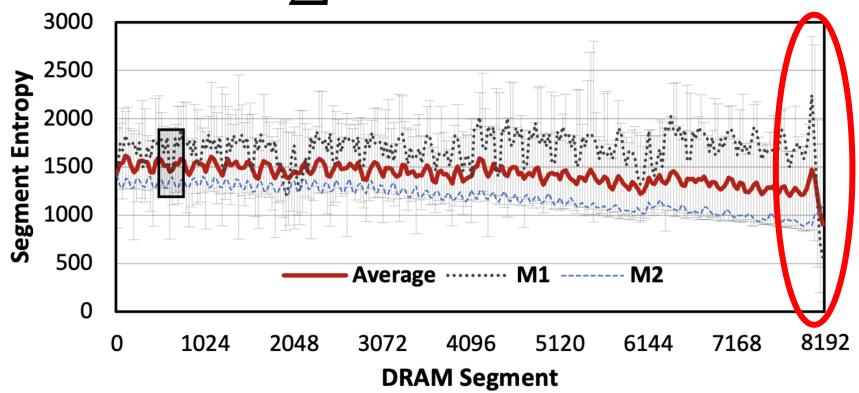
Segment entropy =  $\sum_{i=1}^{n} all bitline entropies in the segment$ 



Segment entropy behavior is different for different modules

# **Spatial Distribution**

Segment entropy =  $\sum$  all bitline entropies in the segment



Entropy significantly increases towards the end of the DRAM bank

# **Takeaways: QUAC Entropy**

- We observe that entropy resulting from QUAC operations changes according to the
- data pattern used in initialization
- physical location of DRAM segments
- attributed to:
- systematic manufacturing process variation
- design-induced variation



## **QUAC-TRNG's Quality**

Two experiments:

- 1. Collect bitstreams by repeatedly sampling bitlines after QUAC operations
  - 1 Mb bitstreams
  - Post-processing: Von Neumann Corrector
- 2. Collect bitstreams using QUAC-TRNG
  - 1 Gb bitstreams
  - Post-processing: SHA-256



## **QUAC-TRNG's Quality**

Two experiments:

- 1. Collect bitstreams by repeatedly sampling bitlines after QUAC operations
  - 1 Mb bitstreams
  - Post-processing: Von Neumann Corrector

QUAC and QUAC-TRNG bitstreams pass all 15 NIST randomness tests

• Post-processing: SHA-256



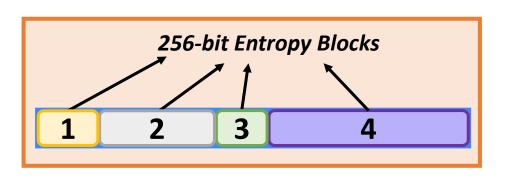
Estimate QUAC-TRNG's throughput according to:

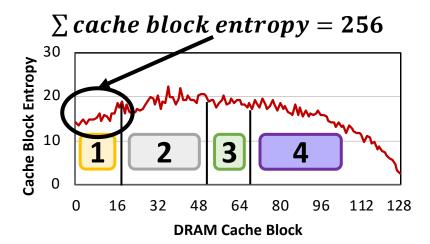
$$(256 \times SIB)/(L \times 10^{-9})$$
 bps



Estimate QUAC-TRNG's throughput according to:

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## **QUAC-TRNG Configurations**

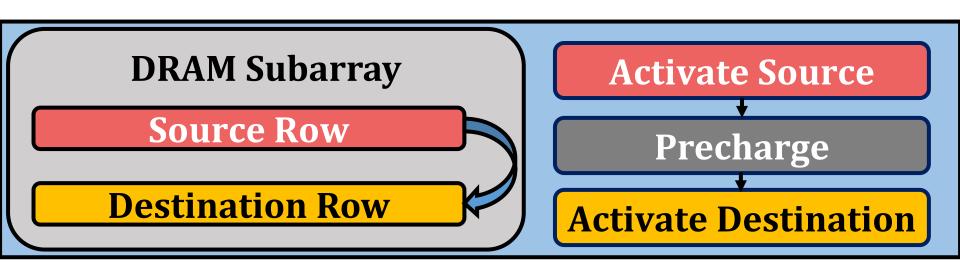


RC + BGP

Use a single DRAM bank

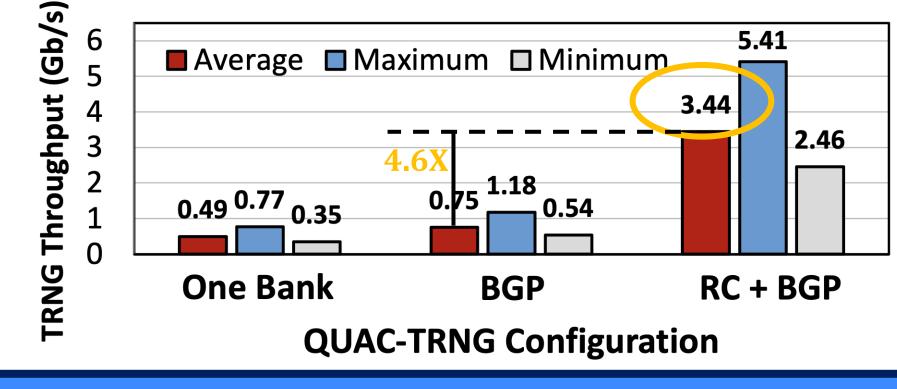
Bank Group-Level Parallelism Use four banks from different bank groups

**RowClone + BGP** Use in-DRAM copy to initialize DRAM rows and use four banks from different bank groups



kasırga [Seshadri+ MICRO'13] [Gao+ MICRO'19] SAFARI

# **QUAC-TRNG Throughput**



Achieves 3.44 Gb/s throughput per DRAM channel on average across all modules

In-DRAM initialization greatly improves throughput

## **QUAC-TRNG vs State-Of-The-Art**

- High-throughput DRAM-based TRNGs:
- **D-RaNGe**: Activation latency failures
- Talukder et. al: Precharge latency failures

Calculate throughput by tightly scheduling the DDR4 commands required to induce failures

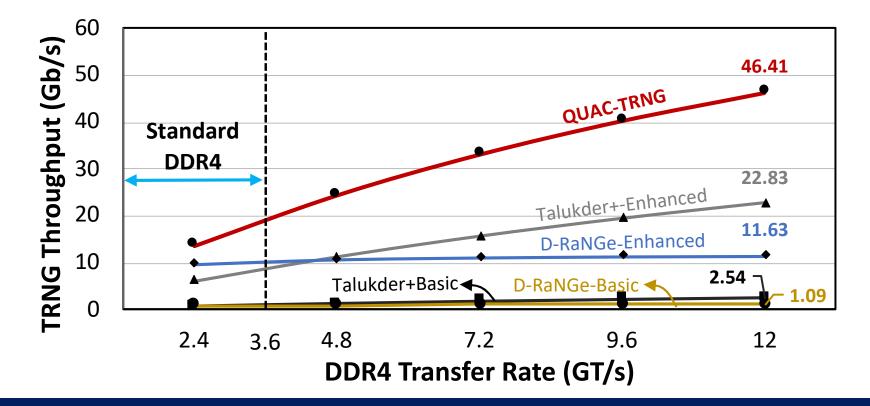
Evaluate two versions of these past two works:

- Base: As proposed
- Enhanced (Fair): Throughput-optimized (SHA-256)

Assume four-channel DDR4 memory

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## **QUAC-TRNG vs State-Of-The-Art**



Outperforms best prior DRAM-based TRNG (i) "base" by 15.08x at 2.4 GT/s (ii) "enhanced" by 2.03x at 12 GT/s

## More in the Paper

- NIST randomness tests results
- Throughput & latency comparison against four other DRAM-based TRNGs
- System Integration
  - How QUAC-TRNG can be implemented in real systems
  - System performance study
    - QUAC-TRNG's throughput with concurrently running applications
  - Area overhead: 0.04% of a contemporary CPU (7 nm)
  - Memory overhead: 0.002% of an 8 GiB DRAM module
- Sensitivity Analysis
  - Effect of temperature on QUAC's entropy
    - Entropy changes with temperature
  - Time dependence study
    - Entropy remains stable for at least up to a month

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- <u>QUAC-TRNG:</u> DRAM-based TRNG that generates true random numbers at **high-throughput** and **low-latency** by **repeatedly performing QUAC operations**
- **<u>Results:</u>** We evaluate QUAC-TRNG using **136** real DDR4 chips
  - 1. **5.4 Gb/s** maximum (**3.4 Gb/s** average) TRNG throughput per DRAM channel
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  - 3. Outperforms existing DRAM-based TRNGs by 15.08x (base), and 1.41x (enhanced)
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## QUAC-TRNG

High-Throughput True Random Number Generation Using Quadruple Row Activation in Real DRAM Chips

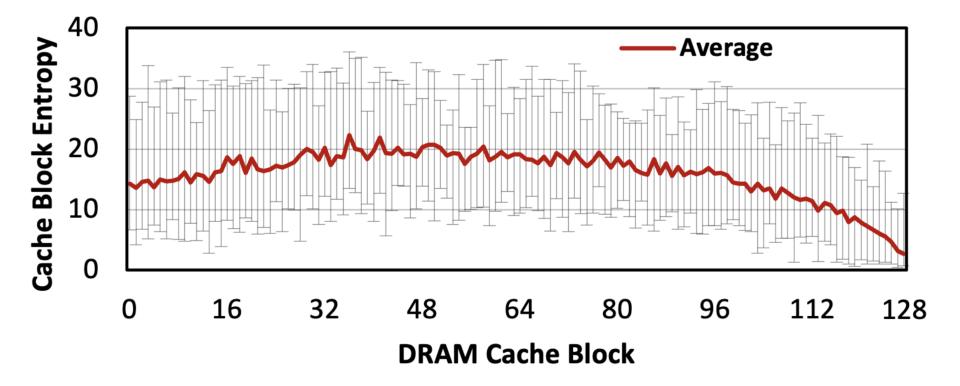
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## **Spatial Distribution**



#### Cache block entropy is the highest around the middle of the DRAM segment



### **NIST Results**

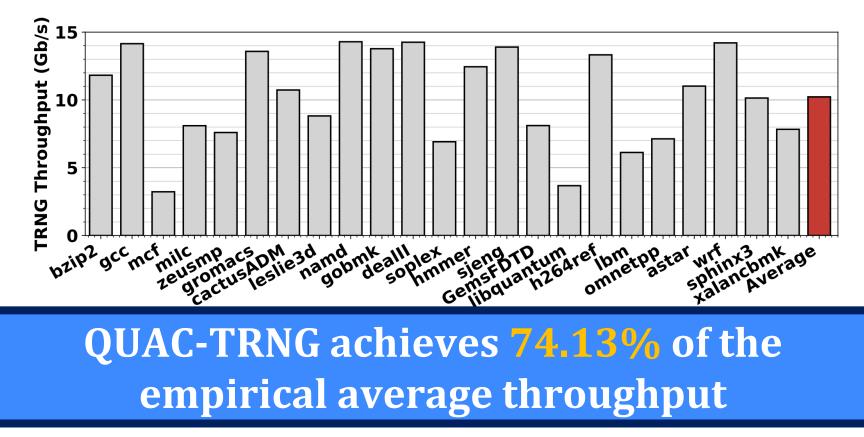
Table 1: NIST STS Randomness Test Results							
NIST STS Test	VNC* (p-value)	SHA-256 (p-value)					
monobit	0.430	0.500					
frequency_within_block	0.408	0.528					
runs	0.335	0.558					
longest_run_ones_in_a_block	0.564	0.533					
binary_matrix_rank	0.554	0.548					
dft	0.538	0.364					
non_overlapping_template_matching	>0.999	0.488					
overlapping_template_matching	0.513	0.410					
maurers_universal	0.493	0.387					
linear_complexity	0.483	0.559					
serial	0.355	0.510					
approximate_entropy	0.448	0.539					
cumulative_sums	0.356	0.381					
random_excursion	0.164	0.466					
random_excursion_variant	0.116	0.510					

\*VNC: Von Neumann Corrector



# **System Performance Study**

The maximum throughput QUAC-TRNG provides without reducing the total off-chip memory bandwidth **Ramulator:** 3.2 GHz core, four-channel DDR4 memory



#### Table 2: Summary of prior DRAM-TRNGs vs QUAC-TRNG

Proposal	Entropy	TRNG	256-bit TRNG		
	Source	Throughput	Latency		
<b>QUAC-TRNG</b>	Quadruple ACT	13.76 Gb/s	274 ns		
Talukder+ [15]	Precharge Failure	0.68 - 6.13 Gb/s	249 ns - 201 ns		
D-RaNGe [88]	Activation Failure	0.92 - 9.73 Gb/s	260 ns - 36 ns		
D-PUF [150]	Retention Failure	0.20 Mb/s	40 s		
DRNG [47]	DRAM Start-up	N/A	700 μs		
Keller+ [81]	Retention Failure	0.025 Mb/s	40 s		
Pyo+ [126]	DRAM Cmd Schedule	2.17 Mb/s	112.5 μs		



### **Temperature Dependence**

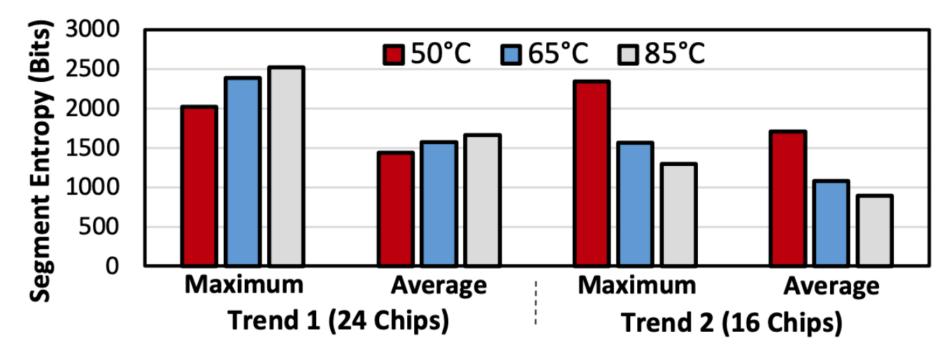


Figure 14: Maximum and average segment entropy at different temperatures.



## **DDR4 Modules**

Module	Module Identifier Chip Identifier		Organization		Segment Entropy				
		Chip Identifier	Freq. (MT/s)	Size (GB)	Chips	Pins	Avg.	Max.†	Avg. (after 30 days)
M1	Unknown	H5AN4G8NAFR-TFC	2133	4	8	x8	1688.1	2247.4	-
M2	Unknown	Unknown	2133	4	8	x8	1180.4	1406.1	-
M3	Unknown	H5AN4G8NAFR-TFC	2133	4	8	x8	1205.0	1858.3	1192.9
M4	76TT21NUS1R8-4G	H5AN4G8NAFR-TFC	2133	4	8	x8	1608.1	2406.5	1588.0
M5	Unknown	T4D5128HT-21	2133	4	8	x8	1618.2	2121.6	-
M6	TLRD44G2666HC18F-SBK	H5AN4G8NMFR-VKC	2666	4	8	x8	1211.5	1444.6	-
M7	TLRD44G2666HC18F-SBK	H5AN4G8NMFR-VKC	2666	4	8	x8	1177.7	1404.4	-
M8	TLRD44G2666HC18F-SBK	H5AN4G8NMFR-VKC	2666	4	8	x8	1332.9	1600.9	1407.0
M9	TLRD44G2666HC18F-SBK	H5AN4G8NMFR-VKC	2666	4	8	x8	1137.1	1370.9	-
M10	TLRD44G2666HC18F-SBK	H5AN4G8NMFR-VKC	2666	4	8	x8	1208.5	1473.2	1251.8
M11	TLRD44G2666HC18F-SBK	H5AN4G8NMFR-VKC	2666	4	8	x8	1176.0	1382.9	1165.1
M12	TLRD44G2666HC18F-SBK	H5AN4G8NMFR-VKC	2666	4	8	x8	1485.0	1740.6	-
M13	KSM32RD8/16HDR	H5AN4G8NAFA-UHC	2400	4	8	x8	1853.5	2849.6	-
M14	F4-2400C17S-8GNT	H5AN4G8NMFR-UHC	2400	8	8	x8	1369.3	1942.2	-
M15	F4-2400C17S-8GNT	H5AN4G8NMFR-UHC	3200	8	8	x8	1545.8	2147.2	-
M16	KSM32RD8/16HDR	H5AN8G8NDJR-XNC	3200	16	8	x8	1634.4	1944.6	-
M17	KSM32RD8/16HDR	H5AN8G8NDJR-XNC	3200	16	8	x8	1664.7	2016.6	-

<sup>†</sup>The maximum possible entropy in a DRAM segment is 64K (65,536) bits.